

ZXTN25020DFL 20V, SOT23, NPN low power transistor

Summary

BV_{CEX} > 100V

 $BV_{CEO} > 20V$

 $BV_{ECO} > 5V$

 $I_{C(cont)} = 2A$

 $I_{CM} = 8A$

 $V_{CE(sat)} < 70mV @ 1A$

 $R_{CE(sat)} = 55m\Omega$

 $P_{D} = 350 \text{mW}$

Complementary part number ZXTP25020DFL



Advanced process capability has been used to achieve high current gain hold up making this device ideal for applications requiring high pulse currents.

Features

- · High peak current
- · Low saturation voltage
- 100V forward blocking voltage

Applications

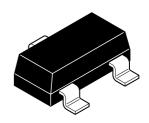
- · MOSFET and IGBT gate driving
- · DC-DC conversion
- · LED driving
- Interface between low voltage IC's and loads

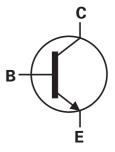
Ordering information

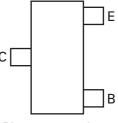
Device	Reel size (inches)	Tape width (mm)	Quantity per reel	
ZXTN25020DFLTA	7	8	3,000	

Device marking

1A1







Pinout - top view

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Collector-base voltage	V _{CBO}	100	V
Collector-emitter voltage (forward blocking)	V _{CEX}	100	V
Collector-emitter voltage	V _{CEO}	20	V
Emitter-collector voltage (reverse blocking)	V _{ECO}	5	V
Emitter-base voltage	V _{EBO}	7	V
Continuous collector current ^(a)	I _C	2	Α
Base current	I _B	500	mA
Peak pulse current	I _{CM}	8	Α
Power dissipation at T _{amb} =25°C ^(a)	P _D	350	mW
Linear derating factor		2.8	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

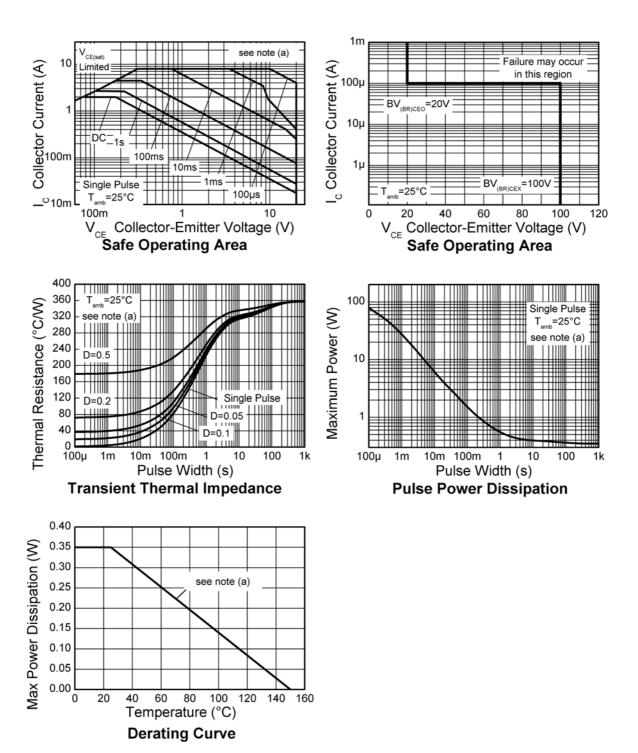
Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^(a)	$R_{\Theta JA}$	357	°C/W

NOTES:

(a) For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

Characteristics



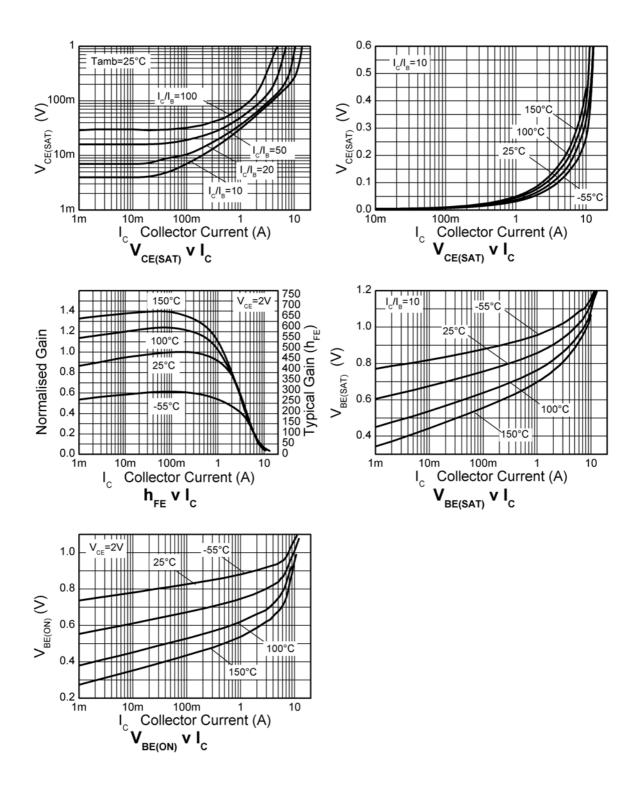
Electrical characteristics (at $T_{amb} = 25$ °C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Collector-base breakdown voltage	BV _{CBO}	100	125		V	I _C = 100μA
Collector-emitter breakdown voltage (forward blocking)	BV _{CEX}	100	120		V	$I_C = 100 \text{ A; } R_{BE} < 1 \text{k}\Omega \text{ or}$ -1V < V _{BE} < 0.25V
Collector-emitter breakdown voltage (base open)	BV _{CEO}	20	35		V	I _C = 10mA ^(*)
Emitter-collector breakdown voltage (reverse blocking)	BV _{ECX}	6	8		V	I_E = 100μA, R_{BC} < 1k Ω or 0.25V > V_{BC} > -0.25V
Emitter-collector breakdown voltage (base open)	BV _{ECO}	5	6		V	$I_E = 100 \mu A$,
Emitter-base breakdown voltage	BV _{EBO}	7	8.3		V	I _E = 100μA
Collector cut-off current	I _{CBO}		<1	50 20	nA μA	$V_{CB} = 80V$ $V_{CB} = 80V, T_{amb} = 100^{\circ}C$
Collector-emitter cut-off current	I _{CEX}		-	100	nA	$V_{CE} = 80V; R_{BE} < 1k\Omega \text{ or}$ -1V < $V_{BE} < 0.25V$
Emitter cut-off current	I _{EBO}		<1	50	nA	V _{EB} = 5.6V
Collector-emitter saturation	V _{CE(SAT)}		60	70	mV	$I_C = 1A, I_B = 100 \text{mA}^{(*)}$
voltage			85	100	mV	$I_C = 1A, I_B = 20mA^{(*)}$
			140	160	mV	$I_C = 2A$, $I_B = 40mA^{(*)}$
			180	225	mV	$I_C = 2A$, $I_B = 20mA^{(*)}$
			245	270	mV	$I_C = 4,5A, I_B = 450 \text{mA}^{(*)}$
Base-emitter saturation voltage	V _{BE(SAT)}		895	1000	mV	$I_C = 2A$, $I_B = 40mA^{(*)}$
Base-emitter turn-on voltage	V _{BE(ON)}		825	900	mV	$I_C = 2A, V_{CE} = 2V^{(*)}$
Static forward current	h _{FE}	300	450	900		$I_C = 10 \text{mA}, V_{CE} = 2V^{(*)}$
transfer ratio		220	350			$I_C = 2A, V_{CE} = 2V^{(*)}$
		80	120			$I_C = 4.5A, V_{CE} = 2V^{(*)}$
Transition frequency	f _T		215		MHz	I _C = 50mA, V _{CE} = 10V f = 100MHz
Output capacitance	C _{OBO}		16.5	25	pF	V _{CB} = 10V, f = 1MHz ^(*)
Delay time	t _(d)		67.7		ns	V _{CC} = 10V. I _C = 1A,
Rise time	t _(r)		72.2		ns	$I_{B1} = I_{B2} = 10 \text{mA}.$
Storage time	t _(s)		361		ns	
Fall time	t _(f)		63.9		ns	

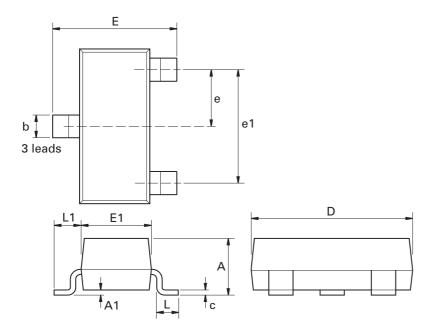
NOTES:

(*) Measured under pulsed conditions. Pulse width $\leq 300 \, \mu s$; duty cycle $\leq 2\%$.

Typical characteristics



Package outline - SOT23



Dim.	Millim	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Max.	Max.
Α	2.67	3.05	0.105	0.120	Н	0.33	0.51	0.013	0.020
В	1.20	1.40	0.047	0.055	K	0.01	0.10	0.0004	0.004
С	-	1.10	-	0.043	L	2.10	2.50	0.083	0.0985
D	0.37	0.53	0.015	0.021	M	0.45	0.64	0.018	0.025
F	0.085	0.15	0.0034	0.0059	N	0.95 NOM 0.0375 NO		NOM	
G	1.90	NOM	0.075	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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WELL and LLV directives.				
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"Not recommended for new d	lesigns" Device is still in production to support existing designs and production			
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"Draft version"	This term denotes a very early datasheet version and contains highly provisional information, which may change in any manner without notice.			
"Provisional version"	This term denotes a pre-release datasheet. It provides a clear indication of anticipated performance. However, changes to the test conditions and specifications may occur, at any time and without notice.			
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